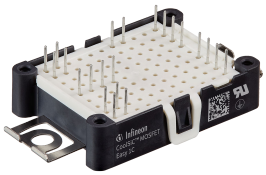
Final datasheet
EasyPACK™ module with CoolSiC™ Trench MOSFET and PressFIT / NTC

Features



- Electrical features
  - V_{DSS} = 750 V
  - I_{DN} = 24 A / I_{DRM} = 72 A
  - Low inductive design
  - Low switching losses
  - High current density
  - Suitable Infineon gate drivers can be found under https://www.infineon.com/gdfinder
- Mechanical features
  - PressFIT contact technology
  - Integrated NTC temperature sensor
  - Rugged mounting due to integrated mounting clamps
  - Package with CTI > 600
  - High current pin

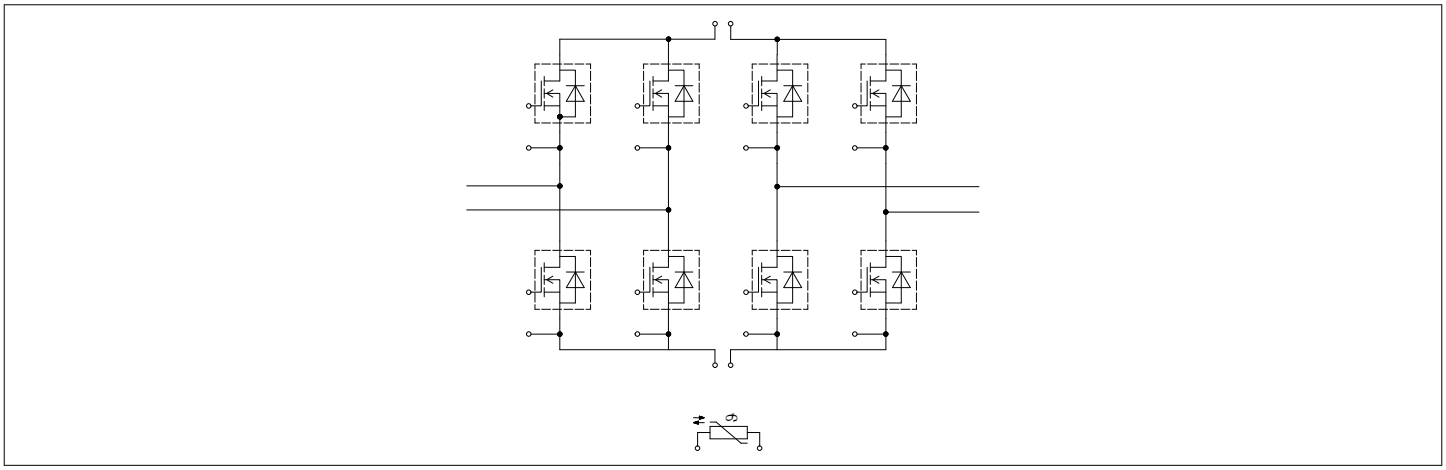
Potential applications

- High-frequency switching application
- DC/DC converter
- EV Auxiliaries
- On-board battery charger - hybrid /EV

Product validation

- Qualified according to AQG 324, release no.: 03.1/2021

Description



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1 Package

Table 1 Insulation coordination

Parameter	Symbol	Note or test condition	Values	Unit
Isolation test voltage	V_{ISOL}	RMS, f = 50 Hz, *t* = 1 min	4.0	kV
Isolation test voltage NTC	$V_{ISOL(NTC)}$	RMS, f = 50 Hz, *t* = 1 min	3.0	kV
Internal isolation		basic insulation (class 1, IEC 61140)	Al_2O_3	
Comparative tracking index	*CTI*		> 600	
Relative thermal index (electrical)	*RTI*	frame	180	°C
		lid	150	

Table 2 Characteristic values

Parameter	Symbol	Note or test condition	Values			Unit
			Min.	Typ.	Max.	
Stray inductance module	L_{sDS}			24		nH
Module lead resistance, terminals - chip	$R_{DD'+SS'}$	T_H = 25 °C, per switch		2.15		mΩ
Storage temperature	T_{stg}		-40		150	°C
Mounting force per clamp	*F*		20		50	N
Weight	*G*			24		g

***Note**: The current up to 50 A per pin is limited by the interaction of the pins with the PCB design and cooling conditions.*

2 MOSFET, T1-T4

Table 3 Maximum rated values

Parameter	Symbol	Note or test condition		Values	Unit
Drain-source voltage	V_{DSS}		T_{vj} = 25 °C	750	V
Implemented drain current	I_{DN}			24	A
Continuous DC drain current	I_{DDC}	T_{vj} = 175 °C, V_{GS} = 18 V	T_H = 105 °C	24	A
Repetitive peak drain current	I_{DRM}	verified by design, t_p limited by T_{vjmax}		72	A
Gate-source voltage, max. transient voltage	V_{GS}	*D* < 0.01		-10/25	V
Gate-source voltage, max. static voltage	V_{GS}			-7/20	V

Table 4 Recommended values

Parameter	Symbol	Note or test condition	Values	Unit
On-state gate voltage	$V_{GS(on)}$		15...18	V
Off-state gate voltage	$V_{GS(off)}$		-5...0	V

Table 5 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Drain-source on-resistance	$R_{DS(on)}$	I_D = 24 A	V_{GS} = 15 V, T_{vj} = 25 °C		22.4		mΩ
			V_{GS} = 18 V, T_{vj} = 25 °C		19.6	28.1	
			V_{GS} = 18 V, T_{vj} = 125 °C		29.2		
			V_{GS} = 18 V, T_{vj} = 175 °C		37.2		
Gate threshold voltage	$V_{GS(th)}$	I_D = 8.2 mA, V_{DS} = V_{GS}, T_{vj} = 25 °C, (tested after 1ms pulse at V_{GS} = +20 V)		3.45	4.1	4.75	V
Total gate charge	Q_G	V_{DD}=400 V, V_{GS} = -3/18 V, T_{vj} = 25 °C			0.052		µC
Internal gate resistor	R_{Gint}	T_{vj}=25 °C			2		Ω
Input capacitance	C_{ISS}	f = 100 kHz, V_{DS}=500 V, V_{GS}=0 V	T_{vj}=25 °C		1.93		nF
Output capacitance	C_{OSS}	f = 100 kHz, V_{DS}=500 V, V_{GS}=0 V	T_{vj}=25 °C		0.135		nF
Reverse transfer capacitance	C_{rss}	f = 100 kHz, V_{DS}=500 V, V_{GS}=0 V	T_{vj}=25 °C		7.52		pF
C_{OSS} stored energy	E_{OSS}	V_{DS}=500 V, V_{GS} = -3/18 V, T_{vj} = 25 °C			20		µJ
Drain-source leakage current	I_{DSS}	V_{DS} = 750 V, V_{GS} = -3 V	T_{vj} = 25 °C			111	µA
Gate-source leakage current	I_{GSS}	V_{DS} = 0 V, T_{vj} = 25 °C	V_{GS}=20 V			400	nA
Turn-on delay time (inductive load)	$t_{d\,on}$	I_D = 24 A, R_{Gon} = 18 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V, t_{dead} = 1000 ns, 0.1 V_{GS} to 0.1 I_D	T_{vj} = 25 °C		15.7		ns
			T_{vj} = 125 °C		15.7		
			T_{vj} = 175 °C		15.4		
Rise time (inductive load)	t_r	I_D = 24 A, R_{Gon} = 18 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V, t_{dead} = 1000 ns, 0.1 I_D to 0.9 I_D	T_{vj} = 25 °C		11.7		ns
			T_{vj} = 125 °C		11		
			T_{vj} = 175 °C		10.8		

(table continues...)

Table 5 (continued) Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Turn-off delay time (inductive load)	$t_{d\ off}$	I_D = 24 A, R_{Goff} = 1 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V, 0.9 V_{GS} to 0.9 I_D	T_{vj} = 25 °C		21		ns
			T_{vj} = 125 °C		22		
			T_{vj} = 175 °C		23		
Fall time (inductive load)	t_f	I_D = 24 A, R_{Goff} = 1 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V, 0.9 I_D to 0.1 I_D	T_{vj} = 25 °C		5.3		ns
			T_{vj} = 125 °C		5.5		
			T_{vj} = 175 °C		5.8		
Turn-on energy loss per pulse	E_{on}	I_D = 24 A, V_{DD} = 400 V, L_σ = 15 nH, V_{GS} = -3/18 V, R_{Gon} = 18 Ω, di/dt = 2.35 kA/µs (T_{vj} = 175 °C), t_{dead} = 1000 ns	T_{vj} = 25 °C		198		µJ
			T_{vj} = 125 °C		215		
			T_{vj} = 175 °C		230		
Turn-on energy loss per pulse, optimized	$E_{on,o}$	I_D = 24 A, V_{DD} = 400 V, L_σ = 15 nH, V_{GS} = -3/18 V, $R_{Gon,o}$ = 16 Ω, di/dt = 2.65 kA/µs (T_{vj} = 175 °C), t_{dead} = 100 ns	T_{vj} = 25 °C		183		µJ
			T_{vj} = 125 °C		182		
			T_{vj} = 175 °C		189		
Turn-off energy loss per pulse	E_{off}	I_D = 24 A, V_{DD} = 400 V, L_σ = 15 nH, V_{GS} = -3/18 V, R_{Goff} = 1 Ω, dv/dt = 61 kV/µs (T_{vj} = 175 °C)	T_{vj} = 25 °C		11.7		µJ
			T_{vj} = 125 °C		11.9		
			T_{vj} = 175 °C		12.6		
Thermal resistance, junction to heat sink	R_{thJH}	per MOSFET, λ_{grease} = 5 W/(m·K)			2.318		K/W
Temperature under switching conditions	$T_{vj\ op}$			-40		175	°C
Temperature under overload switching conditions	$T_{vj\ over}$	Overload, cumulative max. 100 h				200	°C

***Note**: The selection of positive and negative gate-source voltages impacts losses and the long-term behavior of the MOSFET and body diode. The design guidelines described in Application Notes AN 2018-09 and AN 2025-02 must be considered to ensure sound operation of the device over the planned lifetime.*

3 Body diode (MOSFET, T1-T4)

Table 6 Maximum rated values

Parameter	Symbol	Note or test condition		Values	Unit
DC body diode forward current	I_{SD}	T_{vj} = 175 °C, V_{GS} = -3 V	T_H = 65 °C	11	A
Pulsed body diode current	$I_{SD\ pulse}$			72	A

Table 7 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Forward voltage	V_{SD}	I_{SD} = 24 A, V_{GS} = -3 V	T_{vj} = 25 °C		4.38	4.95	V
			T_{vj} = 125 °C		4.08		
			T_{vj} = 175 °C		3.96		
Peak reverse recovery current	I_{rrm}	I_{SD} = 24 A, di_s/dt = 2.35 kA/µs, V_{DD} = 400 V, V_{GS} = -3 V, t_{dead} = 1000 ns	T_{vj} = 25 °C		15.9		A
			T_{vj} = 125 °C		18.9		
			T_{vj} = 175 °C		21.5		
Recovered charge	Q_{rr}	I_{SD} = 24 A, di_s/dt = 2.35 kA/µs, V_{DD} = 400 V, V_{GS} = -3 V, t_{dead} = 1000 ns	T_{vj} = 25 °C		0.141		µC
			T_{vj} = 125 °C		0.187		
			T_{vj} = 175 °C		0.25		
Reverse recovery energy	E_{rec}	I_{SD} = 24 A, di_s/dt = 2.35 kA/µs (T_{vj} = 175 °C), V_{DD} = 400 V, V_{GS} = -3 V, t_{dead} = 1000 ns	T_{vj} = 25 °C		10.2		µJ
			T_{vj} = 125 °C		18.9		
			T_{vj} = 175 °C		29.5		
Reverse recovery energy, optimized	$E_{rec,o}$	I_{SD} = 24 A, di_s/dt = 2.65 kA/µs (T_{vj} = 175 °C), V_{DD} = 400 V, V_{GS} = -3 V, t_{dead} = 100 ns	T_{vj} = 25 °C		11.5		µJ
			T_{vj} = 125 °C		14.4		
			T_{vj} = 175 °C		19.2		

4 MOSFET, T5-T8

Table 8 Maximum rated values

Parameter	Symbol	Note or test condition		Values	Unit
Drain-source voltage	V_{DSS}		T_{vj} = 25 °C	750	V
Implemented drain current	I_{DN}			13	A
Continuous DC drain current	I_{DDC}	T_{vj} = 175 °C, V_{GS} = 18 V	T_H = 125 °C	13	A
Repetitive peak drain current	I_{DRM}	verified by design, t_p limited by T_{vjmax}		39	A
Gate-source voltage, max. transient voltage	V_{GS}	D < 0.01		-10/25	V
Gate-source voltage, max. static voltage	V_{GS}			-7/20	V

Table 9 Recommended values

Parameter	Symbol	Note or test condition	Values	Unit
On-state gate voltage	$V_{GS(on)}$		15...18	V
Off-state gate voltage	$V_{GS(off)}$		-5...0	V

Table 10 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Drain-source on-resistance	$R_{DS(on)}$	I_D = 13 A	V_{GS} = 15 V, T_{vj} = 25 °C		41.4		mΩ
			V_{GS} = 18 V, T_{vj} = 25 °C		36.1	47.9	
			V_{GS} = 18 V, T_{vj} = 125 °C		54		
			V_{GS} = 18 V, T_{vj} = 175 °C		68.8		
Gate threshold voltage	$V_{GS(th)}$	I_D = 4.44 mA, V_{DS} = V_{GS}, T_{vj} = 25 °C, (tested after 1ms pulse at V_{GS} = +20 V)		3.45	4.1	4.75	V
Total gate charge	Q_G	V_{DD}=400 V, V_{GS} = -3/18 V, T_{vj} = 25 °C			0.028		µC
Internal gate resistor	R_{Gint}	T_{vj}=25 °C			0		Ω
Input capacitance	C_{ISS}	f = 100 kHz, V_{DS}=500 V, V_{GS}=0 V	T_{vj}=25 °C		1.11		nF
Output capacitance	C_{OSS}	f = 100 kHz, V_{DS}=500 V, V_{GS}=0 V	T_{vj}=25 °C		0.082		nF
Reverse transfer capacitance	C_{rss}	f = 100 kHz, V_{DS}=500 V, V_{GS}=0 V	T_{vj}=25 °C		3.98		pF
C_{OSS} stored energy	E_{OSS}	V_{DS}=500 V, V_{GS} = -3/18 V, T_{vj} = 25 °C			12.3		µJ
Drain-source leakage current	I_{DSS}	V_{DS} = 750 V, V_{GS} = -3 V	T_{vj} = 25 °C			111	µA
Gate-source leakage current	I_{GSS}	V_{DS} = 0 V, T_{vj} = 25 °C	V_{GS}=20 V			400	nA
Turn-on delay time (inductive load)	$t_{d\,on}$	I_D = 13 A, R_{Gon} = 13 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V, t_{dead} = 1000 ns, 0.1 V_{GS} to 0.1 I_D	T_{vj} = 25 °C		6.8		ns
			T_{vj} = 125 °C		6.1		
			T_{vj} = 175 °C		6.1		
Rise time (inductive load)	t_r	I_D = 13 A, R_{Gon} = 13 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V, t_{dead} = 1000 ns, 0.1 I_D to 0.9 I_D	T_{vj} = 25 °C		6.3		ns
			T_{vj} = 125 °C		6.2		
			T_{vj} = 175 °C		6		
Turn-off delay time (inductive load)	$t_{d\,off}$	I_D = 13 A, R_{Goff} = 1.6 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V, 0.9 V_{GS} to 0.9 I_D	T_{vj} = 25 °C		14.1		ns
			T_{vj} = 125 °C		14.8		
			T_{vj} = 175 °C		15.2		
Fall time (inductive load)	t_f	I_D = 13 A, R_{Goff} = 1.6 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V, 0.9 I_D to 0.1 I_D	T_{vj} = 25 °C		4.9		ns
			T_{vj} = 125 °C		4.8		
			T_{vj} = 175 °C		4.8		

(table continues...)

Table 10 (continued) Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Turn-on energy loss per pulse	E_{on}	I_D = 13 A, V_{DD} = 400 V, L_σ = 15 nH, V_{GS} = -3/18 V, R_{Gon} = 13 Ω, di/dt = 2.6 kA/µs (T_{vj} = 175 °C), t_{dead} = 1000 ns	T_{vj} = 25 °C		89		µJ
			T_{vj} = 125 °C		98		
			T_{vj} = 175 °C		107		
Turn-on energy loss per pulse, optimized	$E_{on,o}$	I_D = 13 A, V_{DD} = 400 V, L_σ = 15 nH, V_{GS} = -3/18 V, $R_{Gon,o}$ = 8.2 Ω, di/dt = 3.75 kA/µs (T_{vj} = 175 °C), t_{dead} = 100 ns	T_{vj} = 25 °C		70		µJ
			T_{vj} = 125 °C		73		
			T_{vj} = 175 °C		73.3		
Turn-off energy loss per pulse	E_{off}	I_D = 13 A, V_{DD} = 400 V, L_σ = 15 nH, V_{GS} = -3/18 V, R_{Goff} = 1.6 Ω, dv/dt = 37.5 kV/µs (T_{vj} = 175 °C)	T_{vj} = 25 °C		1.66		µJ
			T_{vj} = 125 °C		1.71		
			T_{vj} = 175 °C		1.78		
Thermal resistance, junction to heat sink	R_{thJH}	per MOSFET, λ_{grease} = 5 W/(m·K)			2.701		K/W
Temperature under switching conditions	$T_{vj\,op}$			-40		175	°C
Temperature under overload switching conditions	$T_{vj\,over}$	Overload, cumulative max. 100 h				200	°C

***Note**: The selection of positive and negative gate-source voltages impacts losses and the long-term behavior of the MOSFET and body diode. The design guidelines described in Application Notes AN 2018-09 and AN 2025-02 must be considered to ensure sound operation of the device over the planned lifetime.*

5 Body diode (MOSFET, T5-T8)

Table 11 Maximum rated values

Parameter	Symbol	Note or test condition		Values	Unit
DC body diode forward current	I_{SD}	T_{vj} = 175 °C, V_{GS} = -3 V	T_H = 65 °C	11	A
Pulsed body diode current	$I_{SD\,pulse}$			39	A

Table 12 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Forward voltage	V_{SD}	I_{SD} = 13 A, V_{GS} = -3 V	T_{vj} = 25 °C		4.38	4.95	V
			T_{vj} = 125 °C		4.08		
			T_{vj} = 175 °C		3.96		
Peak reverse recovery current	I_{rrm}	I_{SD} = 13 A, di_s/dt = 2.6 kA/µs, V_{DD} = 400 V, V_{GS} = -3 V, t_{dead} = 1000 ns	T_{vj} = 25 °C		18.6		A
			T_{vj} = 125 °C		21		
			T_{vj} = 175 °C		23.5		
Recovered charge	Q_{rr}	I_{SD} = 13 A, di_s/dt = 2.6 kA/µs, V_{DD} = 400 V, V_{GS} = -3 V, t_{dead} = 1000 ns	T_{vj} = 25 °C		0.127		µC
			T_{vj} = 125 °C		0.161		
			T_{vj} = 175 °C		0.198		
Reverse recovery energy	E_{rec}	I_{SD} = 13 A, di_s/dt = 2.6 kA/µs (T_{vj} = 175 °C), V_{DD} = 400 V, V_{GS} = -3 V, t_{dead} = 1000 ns	T_{vj} = 25 °C		12.1		µJ
			T_{vj} = 125 °C		18.7		
			T_{vj} = 175 °C		25.2		
Reverse recovery energy, optimized	$E_{rec,o}$	I_{SD} = 13 A, di_s/dt = 3.75 kA/µs (T_{vj} = 175 °C), V_{DD} = 400 V, V_{GS} = -3 V, t_{dead} = 100 ns	T_{vj} = 25 °C		21.5		µJ
			T_{vj} = 125 °C		26.5		
			T_{vj} = 175 °C		39		

6 NTC-Thermistor

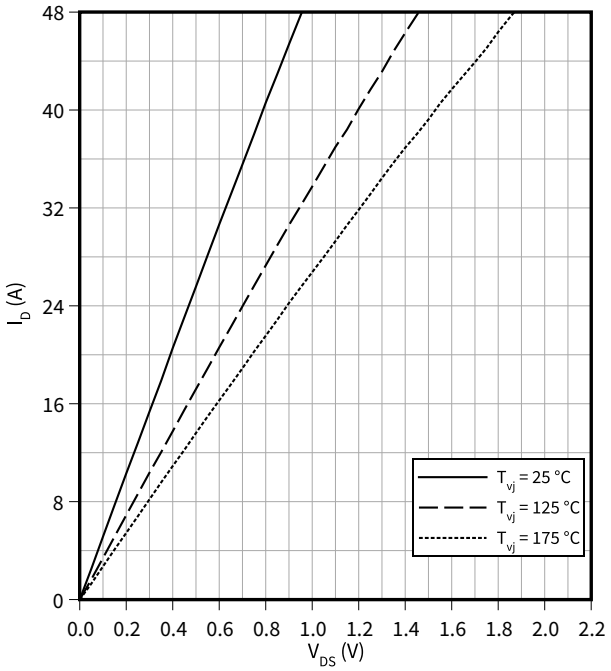
Table 13 Characteristic values

Parameter	Symbol	Note or test condition	Values			Unit
			Min.	Typ.	Max.	
Rated resistance	R_{25}	T_{NTC} = 25 °C		5		kΩ
Deviation of R_{100}	$\Delta R/R$	T_{NTC} = 100 °C, R_{100} = 493 Ω	-5		5	%
Power dissipation	P_{25}	T_{NTC} = 25 °C			20	mW
B-value	$B_{25/50}$	$R_2 = R_{25} \exp[B_{25/50}(1/T_2-1/(298{,}15\ K))]$		3375		K
B-value	$B_{25/80}$	$R_2 = R_{25} \exp[B_{25/80}(1/T_2-1/(298{,}15\ K))]$		3411		K
B-value	$B_{25/100}$	$R_2 = R_{25} \exp[B_{25/100}(1/T_2-1/(298{,}15\ K))]$		3433		K

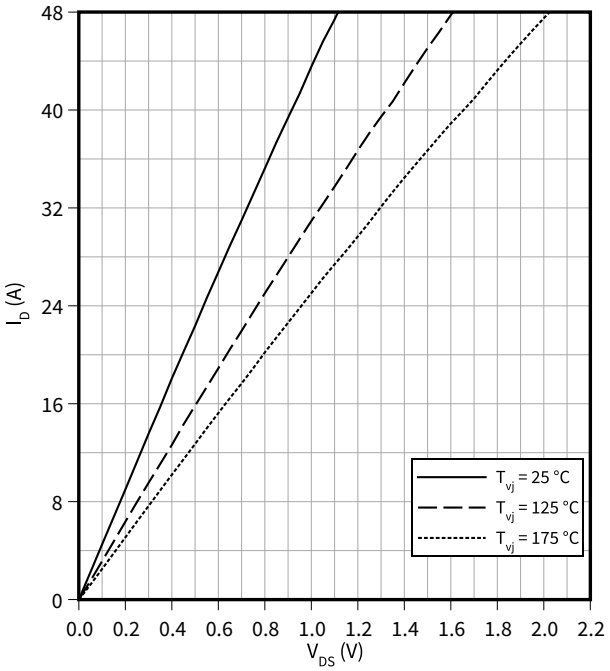
***Note**: For an analytical description of the NTC characteristics please refer to AN2009-10, chapter 4*

7 Characteristics diagrams

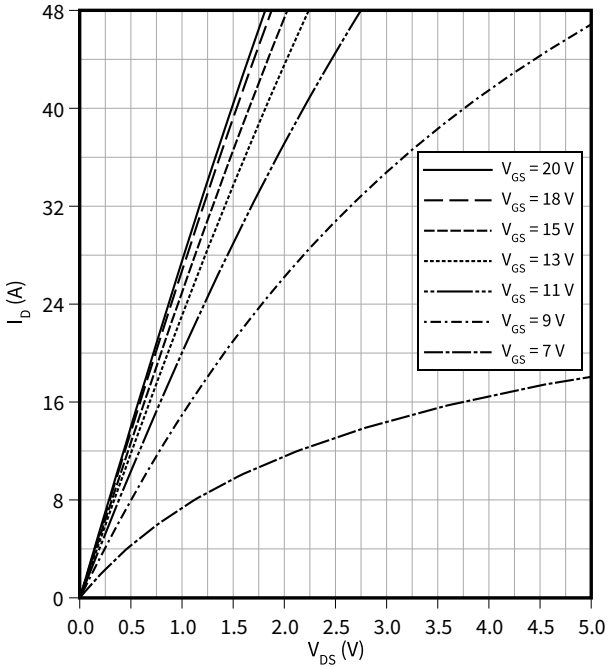
Output characteristic (typical), MOSFET, T1-T4
$I_D = f(V_{DS})$
V_{GS} = 18 V



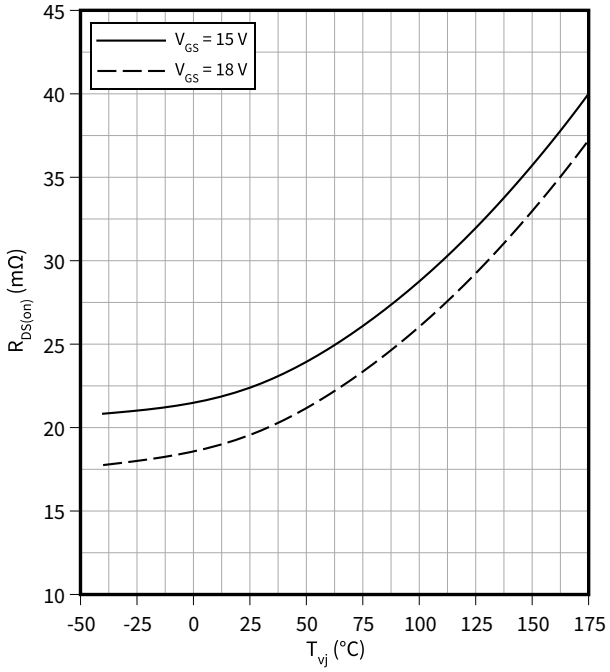
Output characteristic (typical), MOSFET, T1-T4
$I_D = f(V_{DS})$
V_{GS} = 15 V



Output characteristic field (typical), MOSFET, T1-T4
$I_D = f(V_{DS})$
T_{vj} = 175 °C

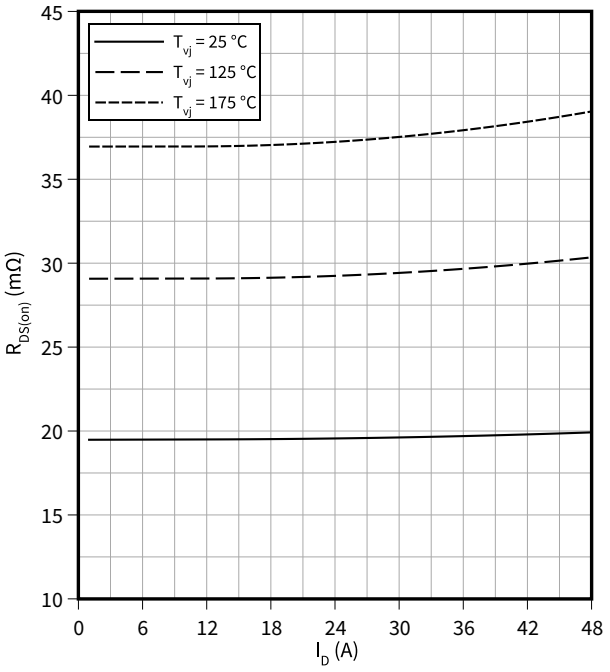


Drain source on-resistance (typical), MOSFET, T1-T4
$R_{DS(on)} = f(T_{vj})$
I_D = 24 A



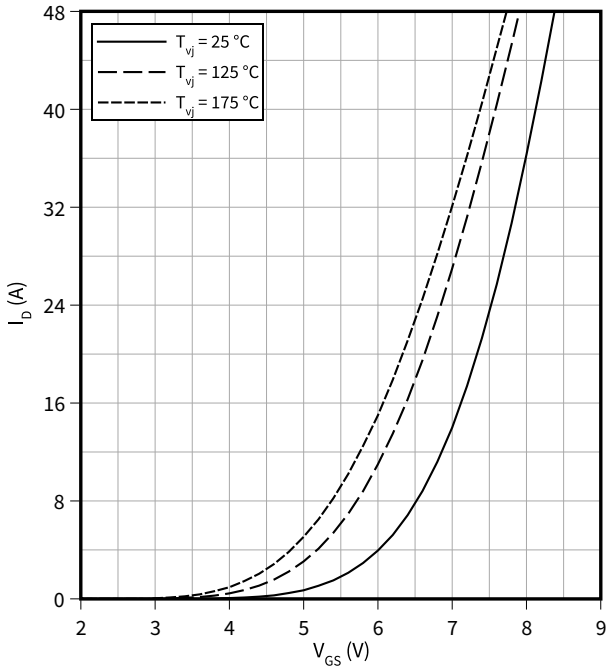
Drain source on-resistance (typical), MOSFET, T1-T4

$R_{DS(on)} = f(I_D)$
$V_{GS} = 18$ V



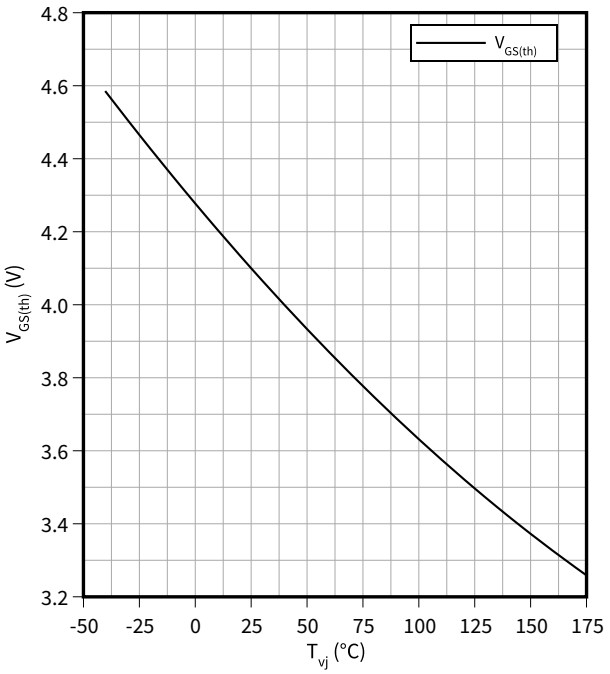
Transfer characteristic (typical), MOSFET, T1-T4

$I_D = f(V_{GS})$
$V_{DS} = 20$ V



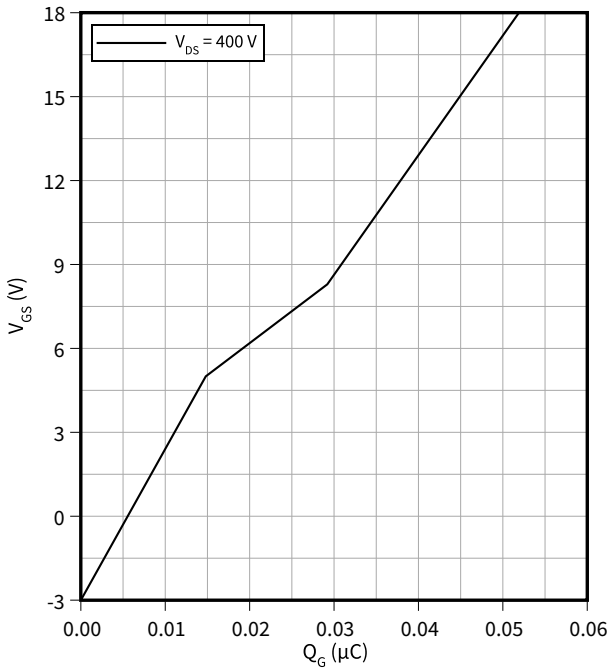
Gate-source threshold voltage (typical), MOSFET, T1-T4

$V_{GS(th)} = f(T_{vj})$
$I_D = 8.2$ mA, $V_{GS} = V_{DS}$



Gate charge characteristic (typical), MOSFET, T1-T4

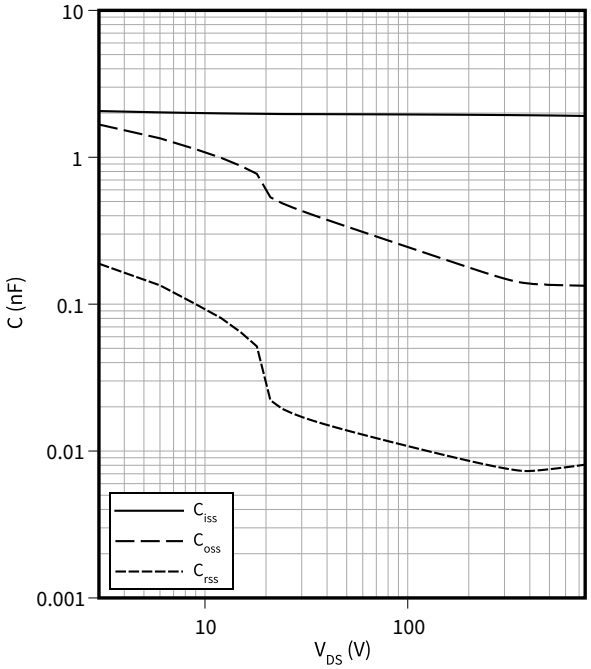
$V_{GS} = f(Q_G)$
$I_D = 24$ A, $T_{vj} = 25$ °C



Capacity characteristic (typical), MOSFET, T1-T4

C = f(V_{DS})

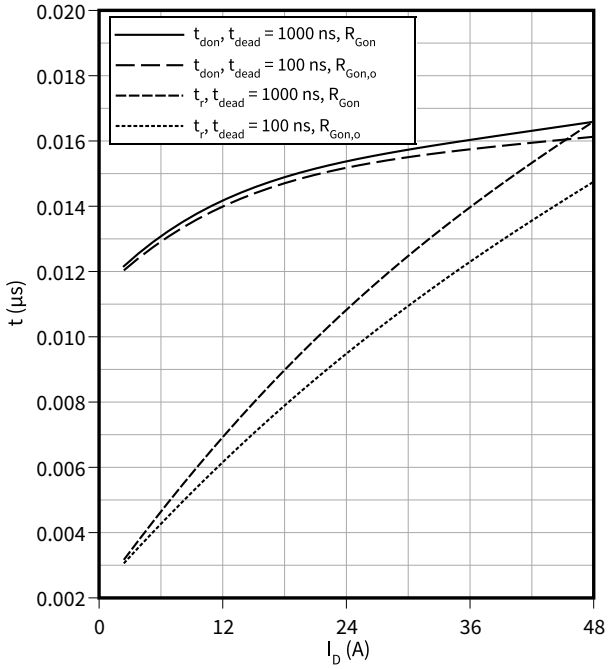
f = 100 kHz, T_{vj} = 25 °C, V_{GS} = 0 V



Switching times (typical), MOSFET, T1-T4

t = f(I_D)

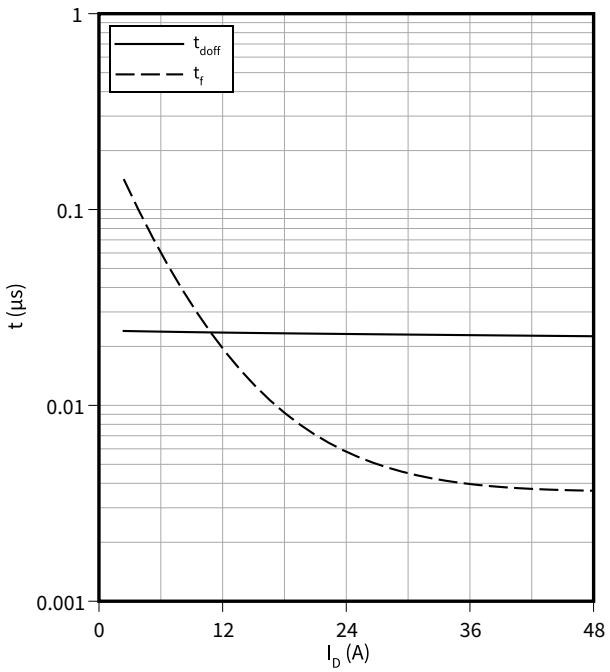
V_{DD} = 400 V, R_{Gon} = 18 Ω, $R_{Gon,o}$ = 16 Ω, T_{vj} = 175 °C, V_{GS} = -3/18 V



Switching times (typical), MOSFET, T1-T4

t = f(I_D)

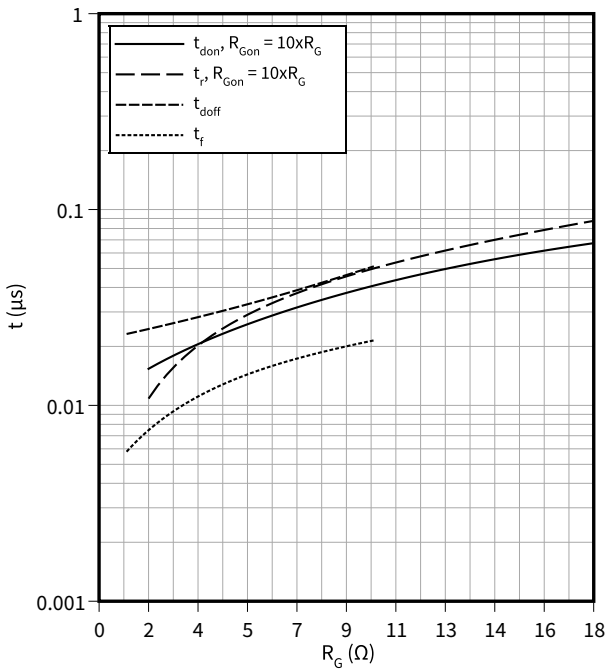
R_{Goff} = 1 Ω, V_{DD} = 400 V, T_{vj} = 175 °C, V_{GS} = -3/18 V



Switching times (typical), MOSFET, T1-T4

t = f(R_G)

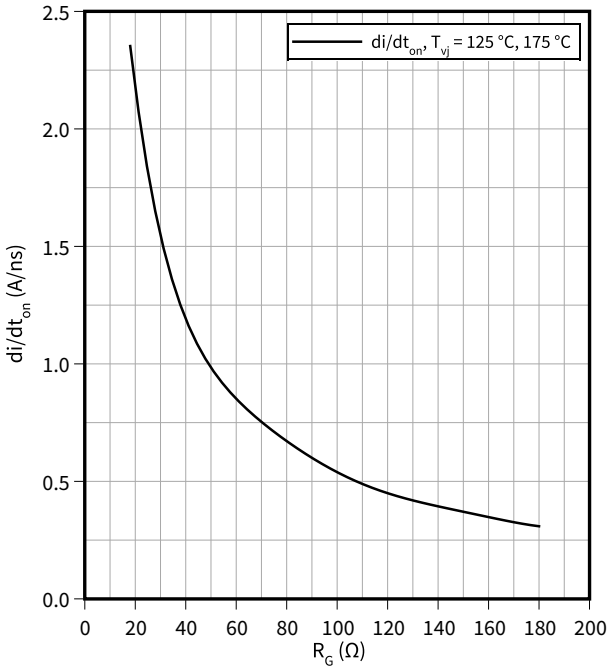
V_{DD} = 400 V, t_{dead} = 1000 ns, I_D = 24 A, T_{vj} = 175 °C, V_{GS} = -3/18 V



Current slope (typical), MOSFET, T1-T4

$di/dt_{on} = f(R_G)$

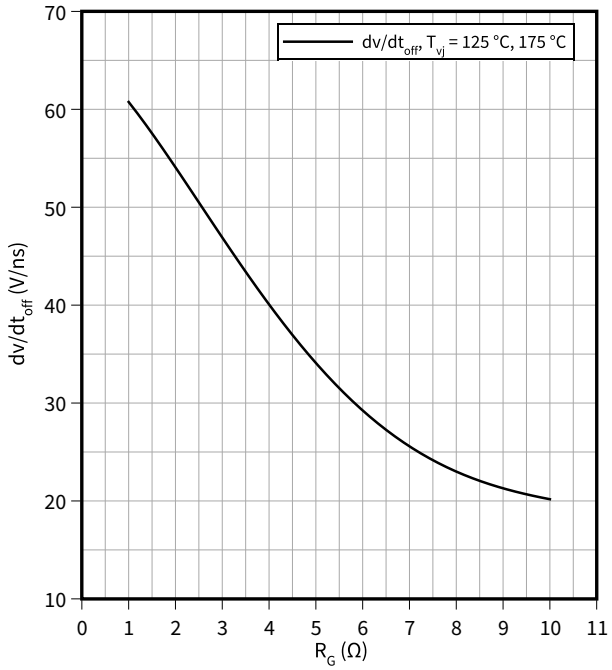
V_{DD} = 400 V, t_{dead} = 1000 ns, I_D = 24 A, V_{GS} = -3/18 V



Voltage slope (typical), MOSFET, T1-T4

$dv/dt_{off} = f(R_G)$

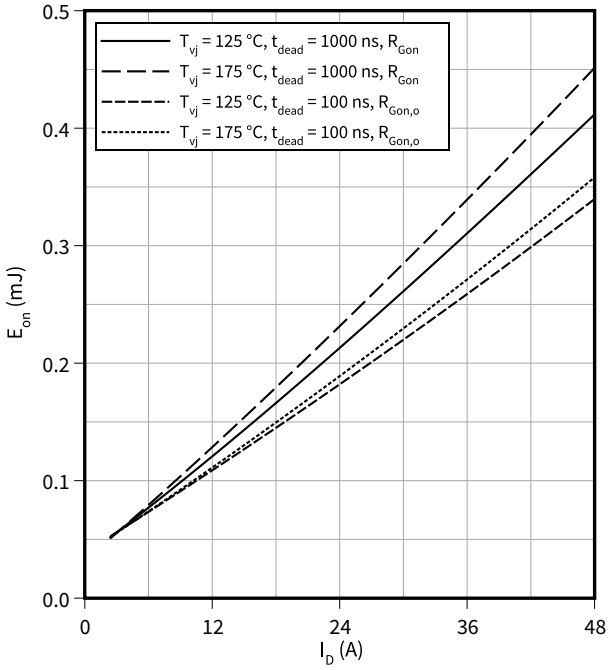
V_{DD} = 400 V, I_D = 24 A, V_{GS} = -3/18 V



Switching losses (typical), MOSFET, T1-T4

$E_{on} = f(I_D)$

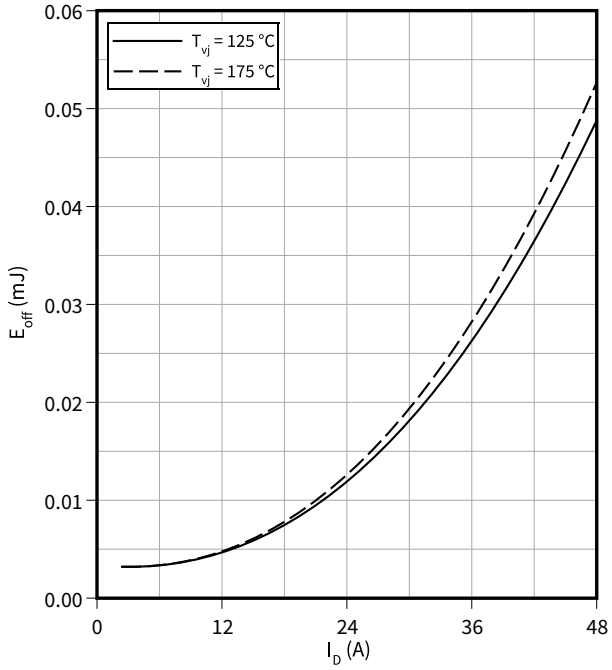
V_{DD} = 400 V, R_{Gon} = 18 Ω, $R_{Gon,o}$ = 16 Ω, V_{GS} = -3/18 V



Switching losses (typical), MOSFET, T1-T4

$E_{off} = f(I_D)$

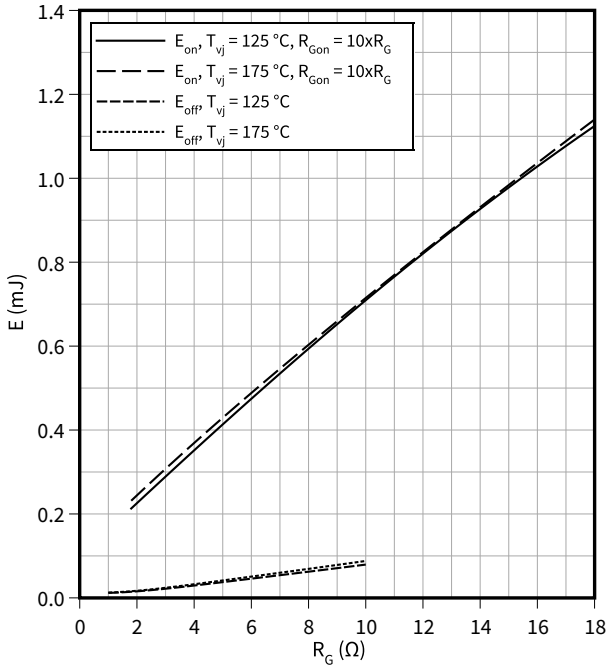
R_{Goff} = 1 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V



Switching losses (typical), MOSFET, T1-T4

$E = f(R_G)$

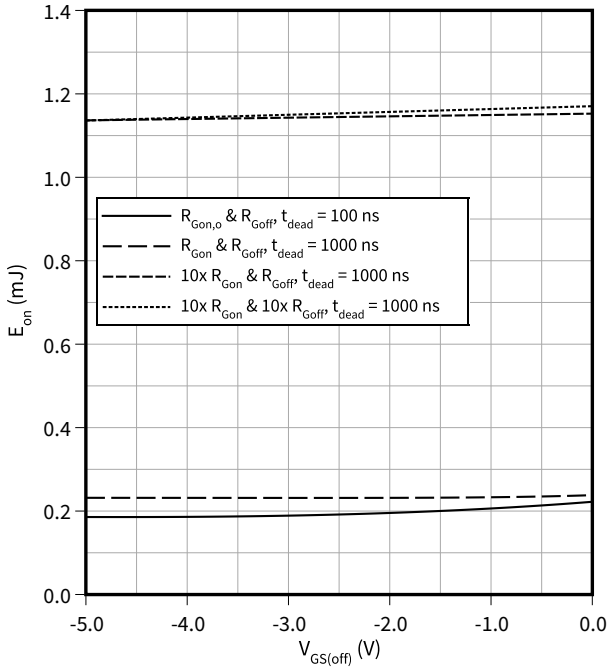
V_{DD} = 400 V, t_{dead} = 1000 ns, I_D = 24 A, V_{GS} = -3/18 V



Switching losses (typical), MOSFET, T1-T4

$E_{on} = f(V_{GS(off)})$

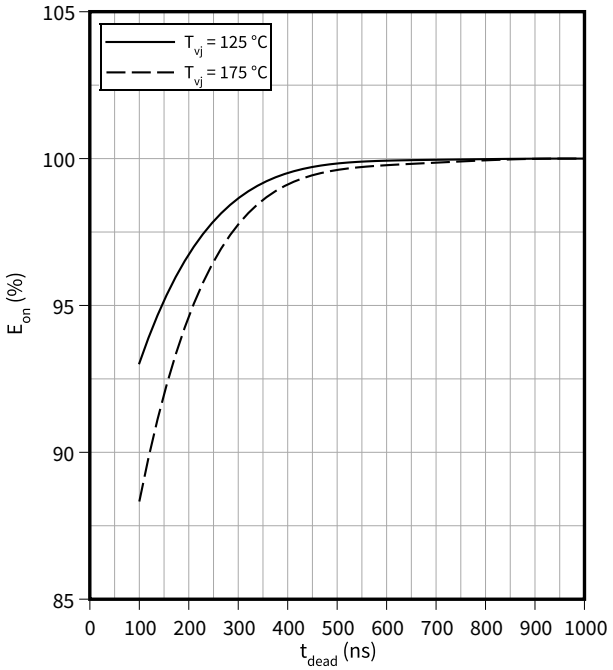
R_{Goff} = 1 Ω, V_{DD} = 400 V, R_{Gon} = 18 Ω, $V_{GS(on)}$ = -3/18 V, I_D = 24 A, $R_{Gon,o}$ = 16 Ω, T_{vj} = 175 °C



Switching losses (typical), MOSFET, T1-T4

$E_{on} = f(t_{dead})$

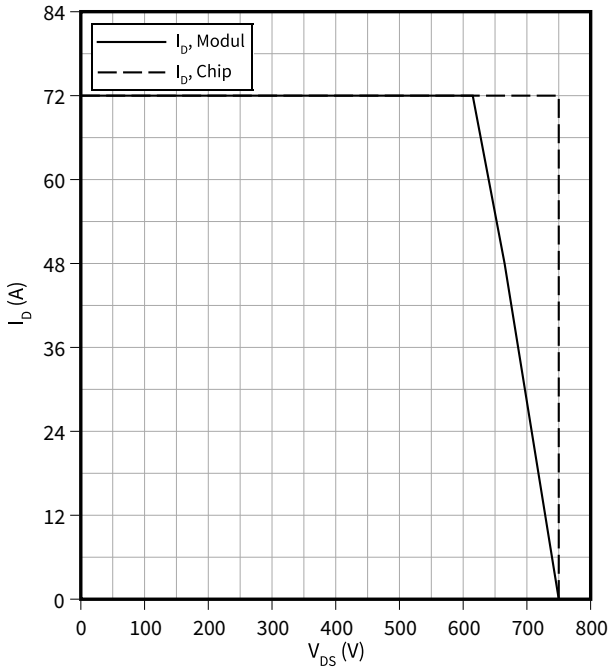
R_{Gon} = 18 Ω, I_D = 24 A, V_{DD} = 400 V, V_{GS} = -3/18 V



Reverse bias safe operating area (RBSOA), MOSFET, T1-T4

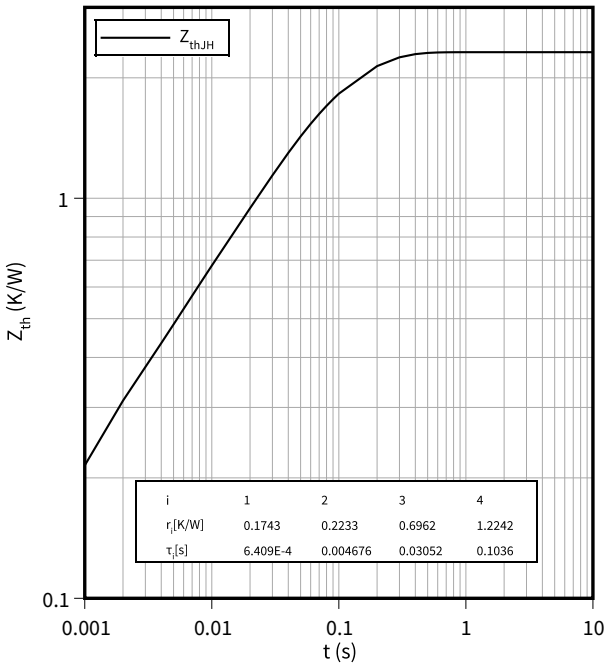
$I_D = f(V_{DS})$

R_{Goff} = 1 Ω, T_{vj} = 175 °C, V_{GS} = -3/18 V



Transient thermal impedance, MOSFET, T1-T4

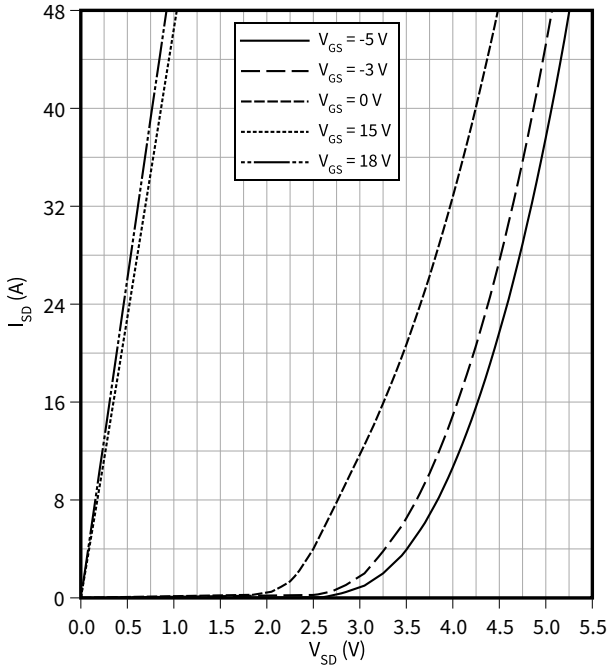
$Z_{th} = f(t)$



Forward characteristic body diode (typical), MOSFET, T1-T4

$I_{SD} = f(V_{SD})$

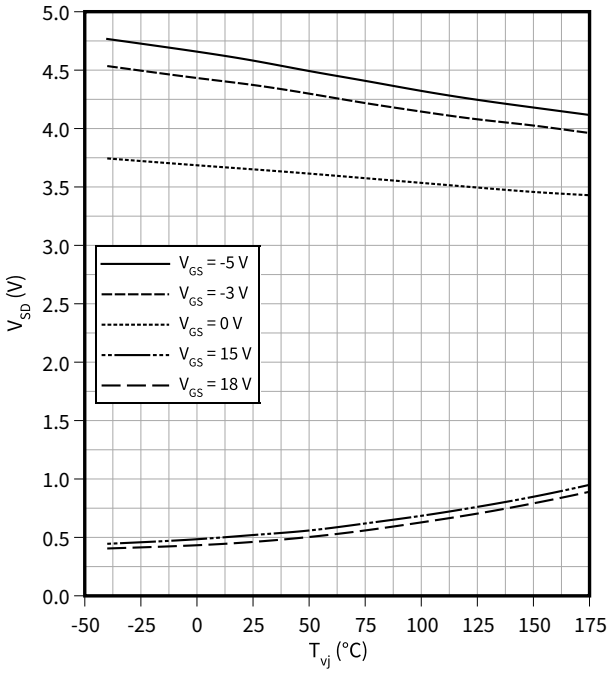
$T_{vj} = 25\ °C$



Forward voltage of body diode (typical), MOSFET, T1-T4

$V_{SD} = f(T_{vj})$

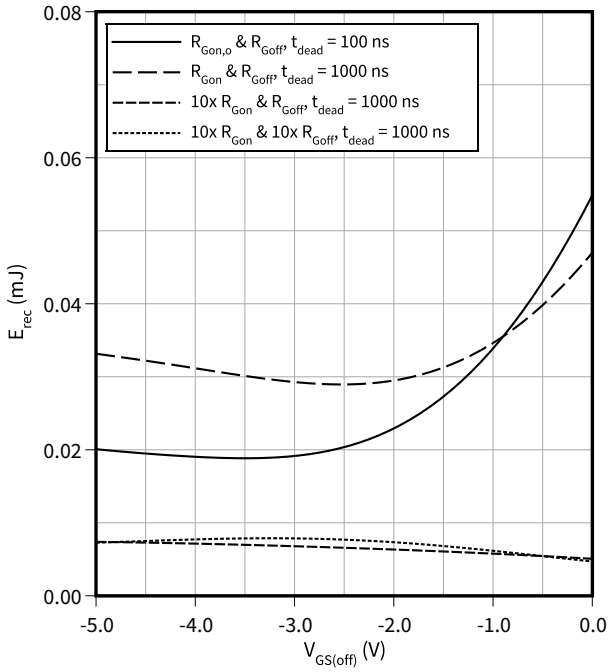
$I_{SD} = 24\ A$



Switching losses body diode (typical), MOSFET, T1-T4

$E_{rec} = f(V_{GS(off)})$

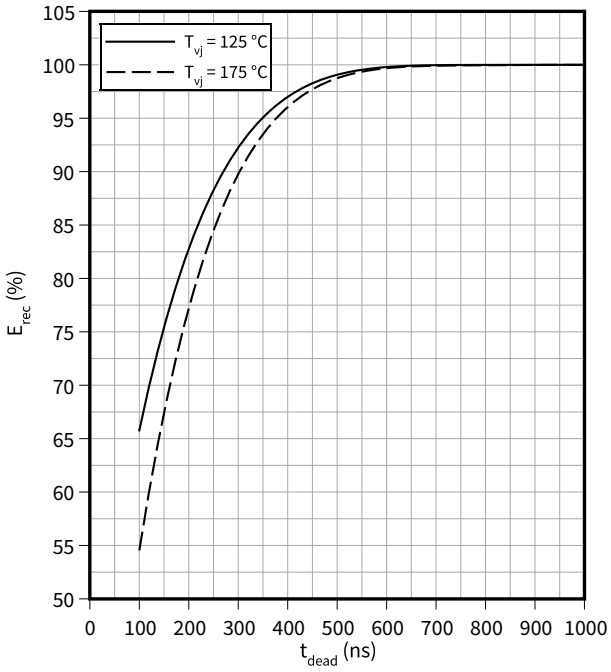
$R_{Goff} = 1\ \Omega$, $R_{Gon} = 18\ \Omega$, $V_{GS(on)} = 18\ V$, $I_{SD} = 24\ A$,
$R_{Gon,o} = 16\ \Omega$, $V_{DD} = 400\ V$, $T_{vj} = 175\ °C$



Switching losses body diode (typical), MOSFET, T1-T4

$E_{rec} = f(t_{dead})$

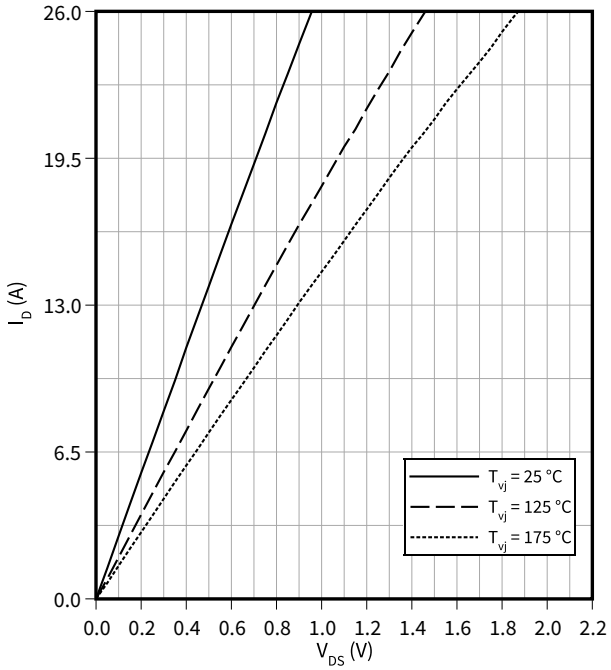
$R_{Gon} = 18\ \Omega$, $I_D = 24$ A, $V_{DD} = 400$ V, $V_{GS} = -3/18$ V



Output characteristic (typical), MOSFET, T5-T8

$I_D = f(V_{DS})$

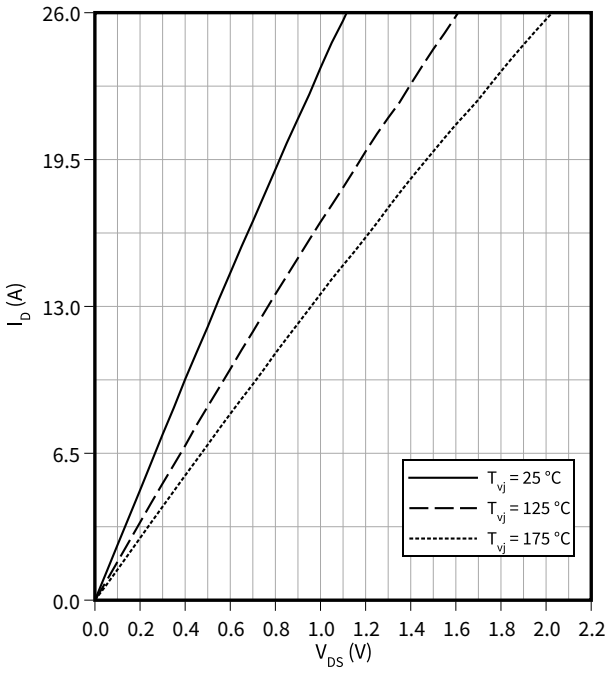
$V_{GS} = 18$ V



Output characteristic (typical), MOSFET, T5-T8

$I_D = f(V_{DS})$

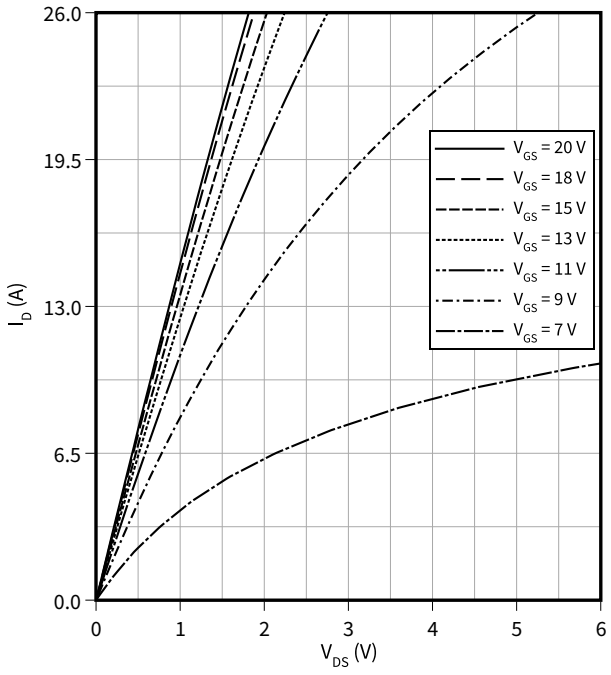
$V_{GS} = 15$ V



Output characteristic field (typical), MOSFET, T5-T8

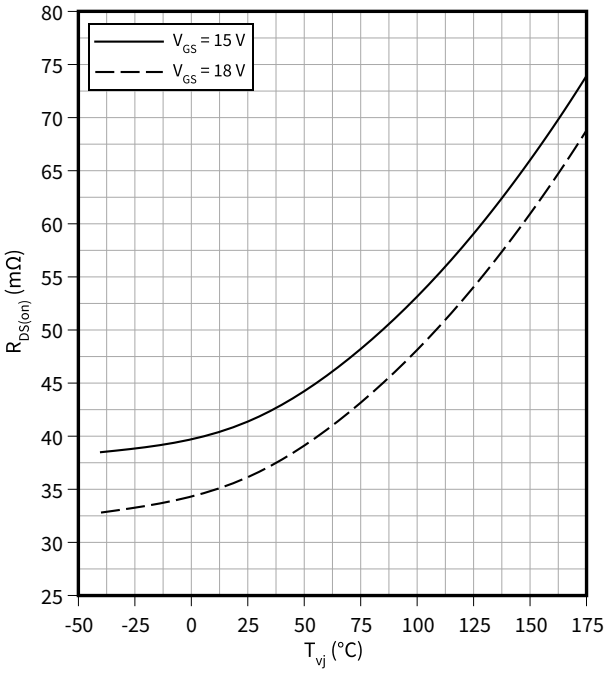
$I_D = f(V_{DS})$

$T_{vj} = 175$ °C



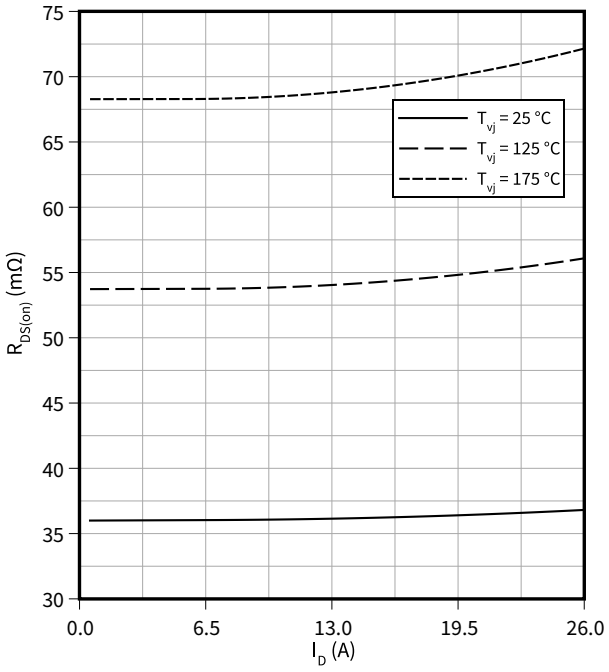
Drain source on-resistance (typical), MOSFET, T5-T8

$R_{DS(on)} = f(T_{vj})$
$I_D = 13$ A



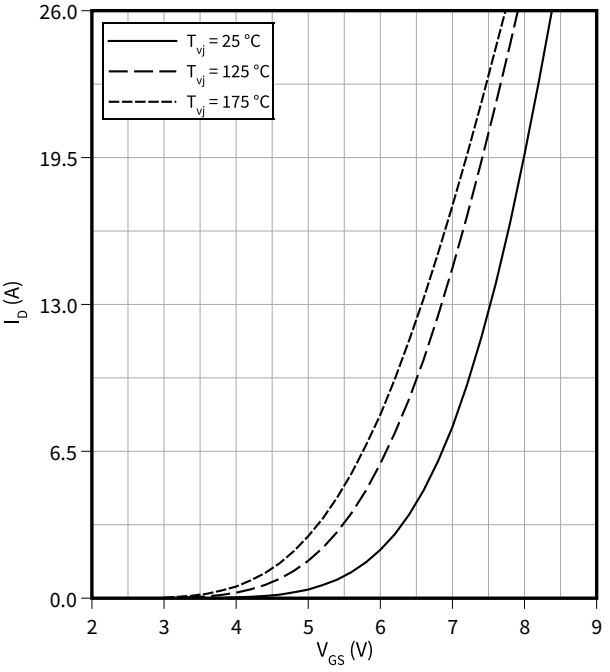
Drain source on-resistance (typical), MOSFET, T5-T8

$R_{DS(on)} = f(I_D)$
$V_{GS} = 18$ V



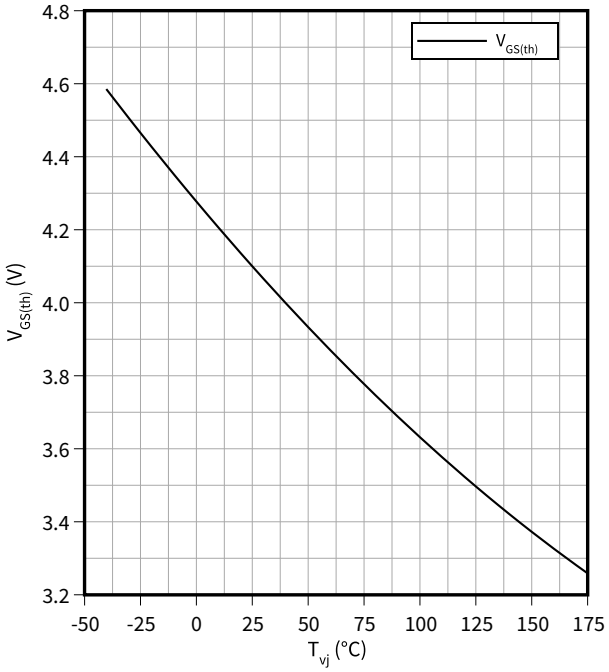
Transfer characteristic (typical), MOSFET, T5-T8

$I_D = f(V_{GS})$
$V_{DS} = 20$ V



Gate-source threshold voltage (typical), MOSFET, T5-T8

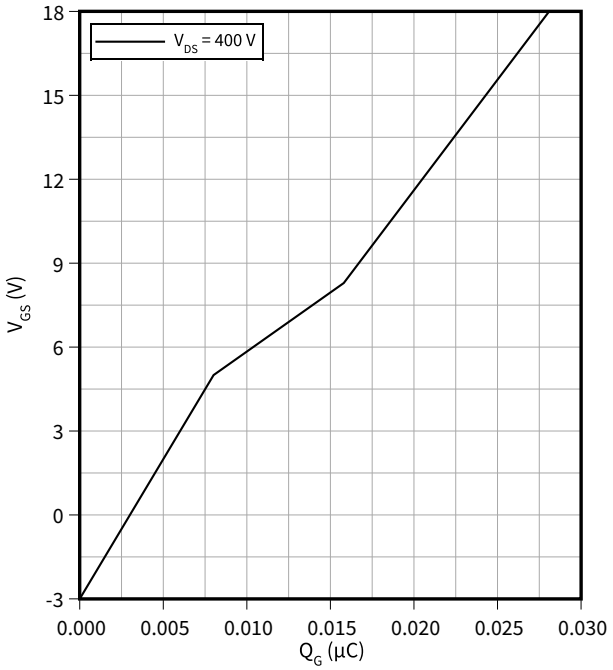
$V_{GS(th)} = f(T_{vj})$
$I_D = 4.44$ mA, $V_{GS} = V_{DS}$



Gate charge characteristic (typical), MOSFET, T5-T8

$V_{GS} = f(Q_G)$

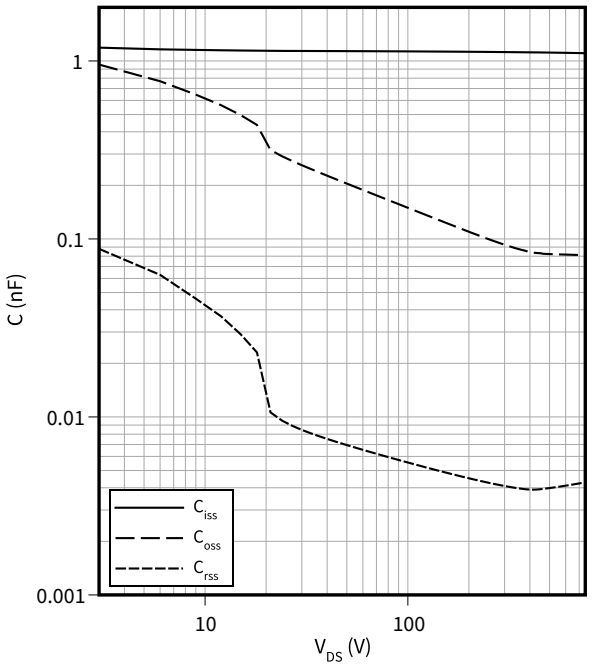
$I_D = 13$ A, $T_{vj} = 25$ °C



Capacity characteristic (typical), MOSFET, T5-T8

$C = f(V_{DS})$

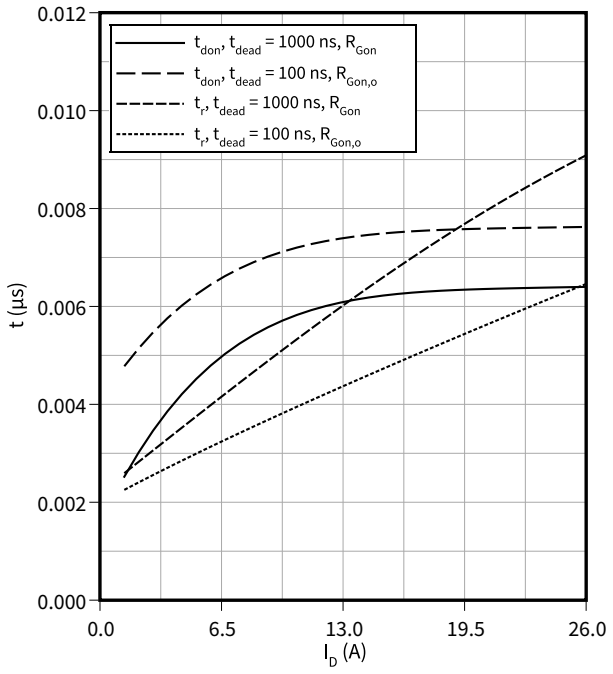
$f = 100$ kHz, $T_{vj} = 25$ °C, $V_{GS} = 0$ V



Switching times (typical), MOSFET, T5-T8

$t = f(I_D)$

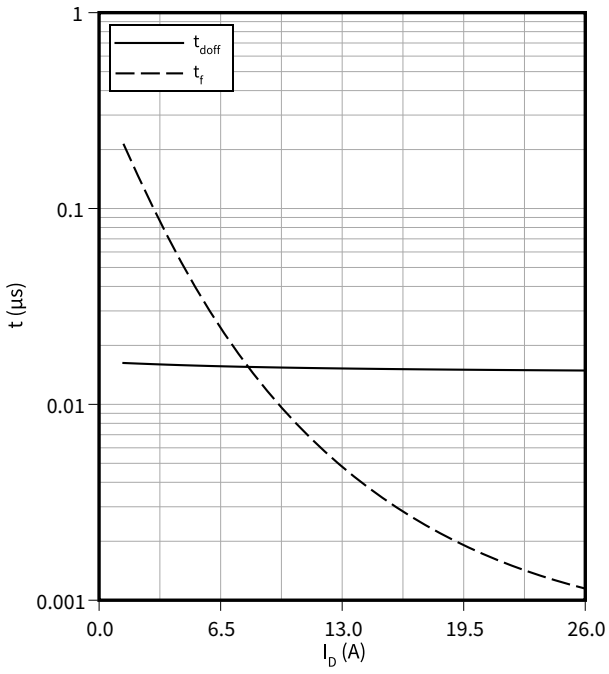
$V_{DD} = 400$ V, $R_{Gon} = 13\ \Omega$, $R_{Gon,o} = 8.2\ \Omega$, $T_{vj} = 175$ °C, $V_{GS} = -3/18$ V



Switching times (typical), MOSFET, T5-T8

$t = f(I_D)$

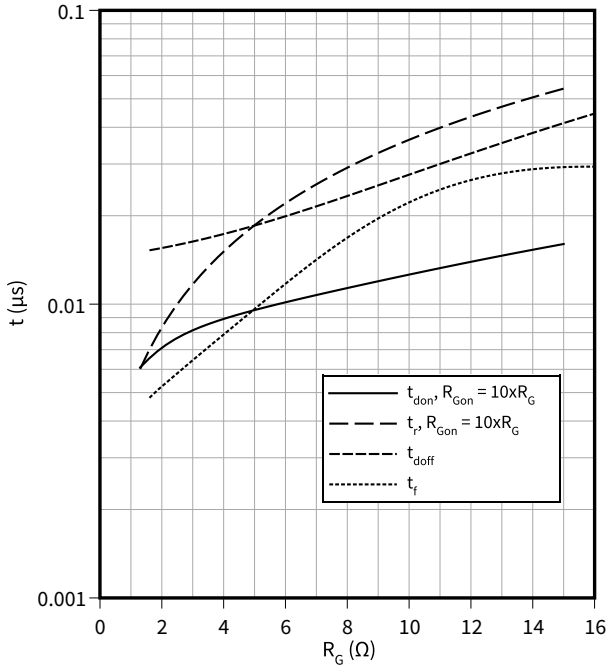
$R_{Goff} = 1.6\ \Omega$, $V_{DD} = 400$ V, $T_{vj} = 175$ °C, $V_{GS} = -3/18$ V



Switching times (typical), MOSFET, T5-T8

$t = f(R_G)$

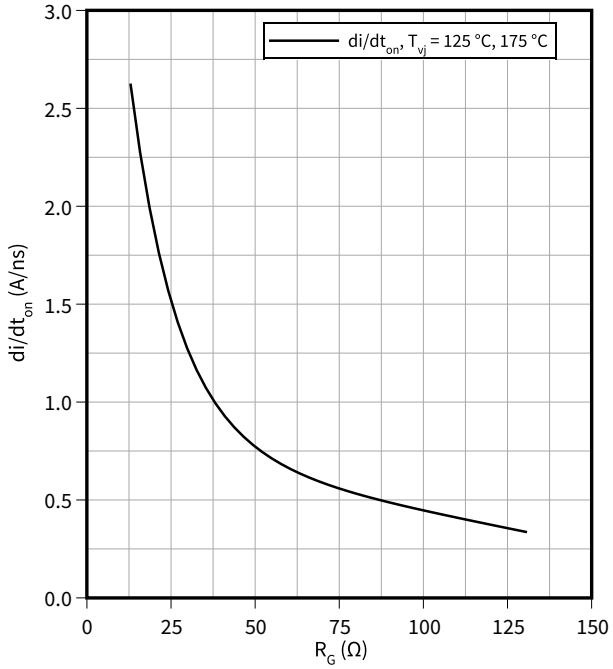
V_{DD} = 400 V, t_{dead} = 1000 ns, I_D = 13 A, T_{vj} = 175 °C, V_{GS} = -3/18 V



Current slope (typical), MOSFET, T5-T8

$di/dt_{on} = f(R_G)$

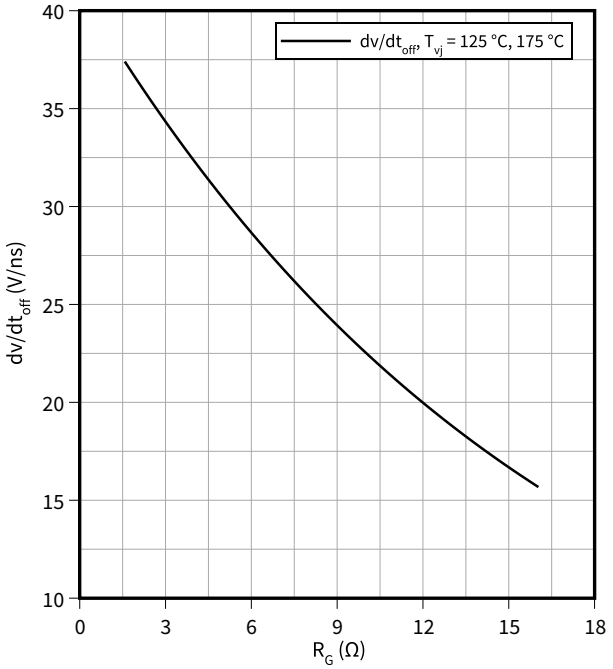
V_{DD} = 400 V, t_{dead} = 1000 ns, I_D = 13 A, V_{GS} = -3/18 V



Voltage slope (typical), MOSFET, T5-T8

$dv/dt_{off} = f(R_G)$

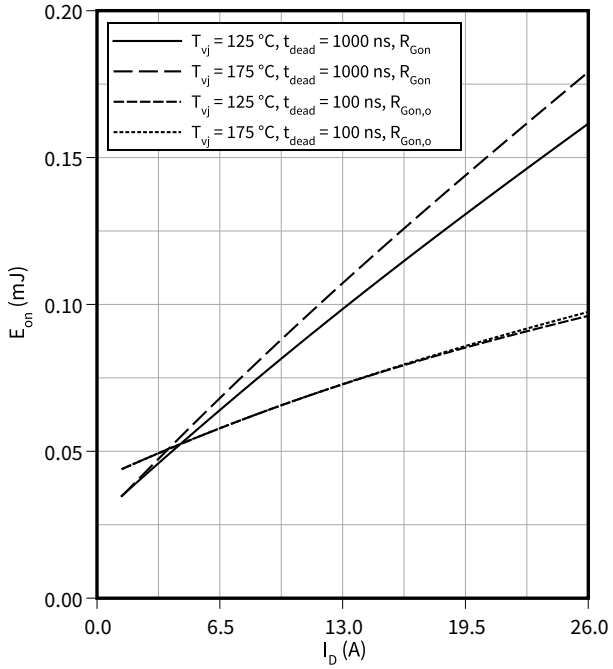
V_{DD} = 400 V, I_D = 13 A, V_{GS} = -3/18 V



Switching losses (typical), MOSFET, T5-T8

$E_{on} = f(I_D)$

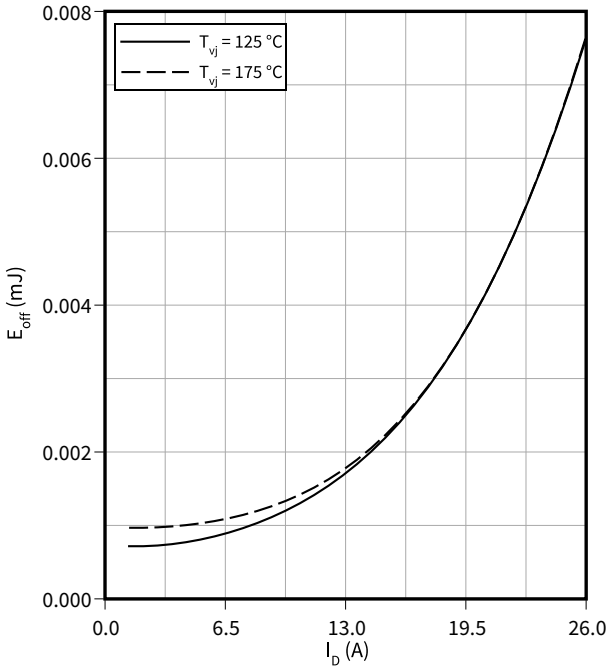
V_{DD} = 400 V, R_{Gon} = 13 Ω, $R_{Gon,o}$ = 8.2 Ω, V_{GS} = -3/18 V



Switching losses (typical), MOSFET, T5-T8

$E_{off} = f(I_D)$

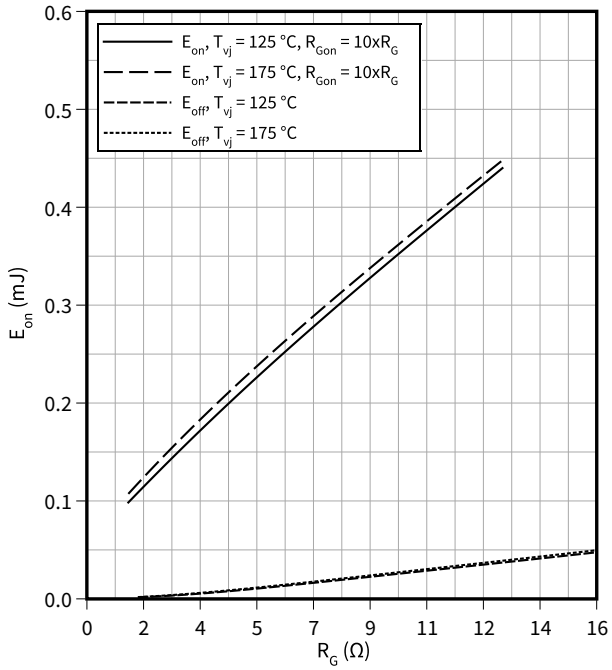
R_{Goff} = 1.6 Ω, V_{DD} = 400 V, V_{GS} = -3/18 V



Switching losses (typical), MOSFET, T5-T8

$E_{on} = f(R_G)$

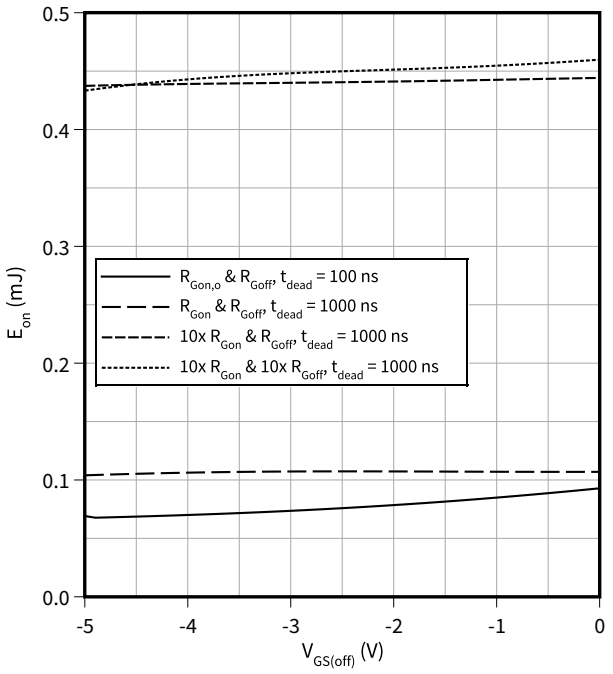
V_{DD} = 400 V, t_{dead} = 1000 ns, I_D = 13 A, V_{GS} = -3/18 V



Switching losses (typical), MOSFET, T5-T8

$E_{on} = f(V_{GS(off)})$

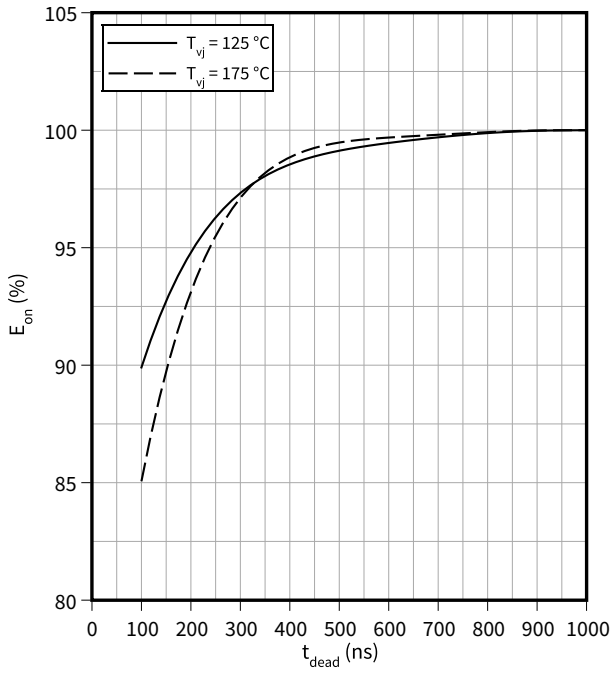
R_{Goff} = 1.6 Ω, V_{DD} = 400 V, R_{Gon} = 13 Ω, $V_{GS(on)}$ = 18 V, I_D = 13 A, $R_{Gon,o}$ = 8.2 Ω, T_{vj} = 175 °C



Switching losses (typical), MOSFET, T5-T8

$E_{on} = f(t_{dead})$

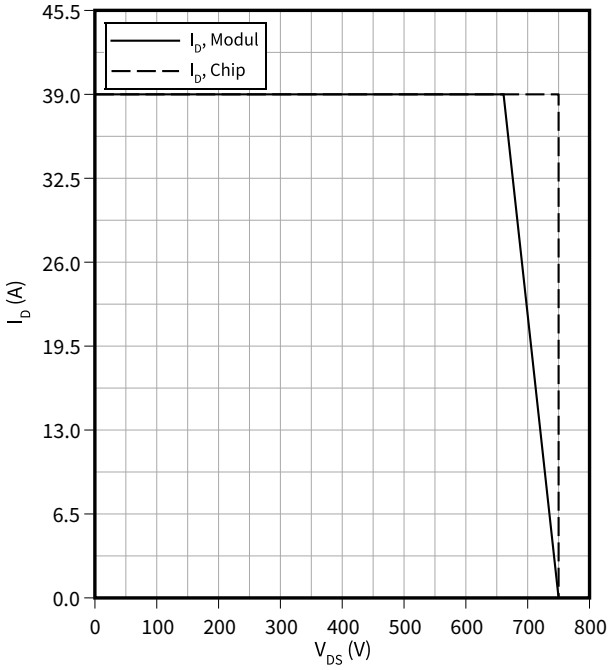
R_{Gon} = 13 Ω, I_D = 13 A, V_{DD} = 400 V, V_{GS} = -3/18 V



Reverse bias safe operating area (RBSOA), MOSFET, T5-T8

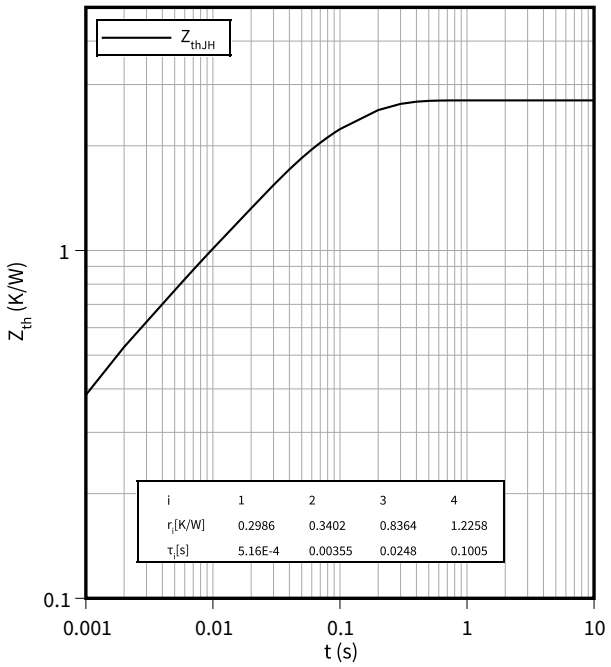
$I_D = f(V_{DS})$

R_{Goff} = 1.6 Ω, T_{vj} = 175 °C, V_{GS} = -3/18 V



Transient thermal impedance, MOSFET, T5-T8

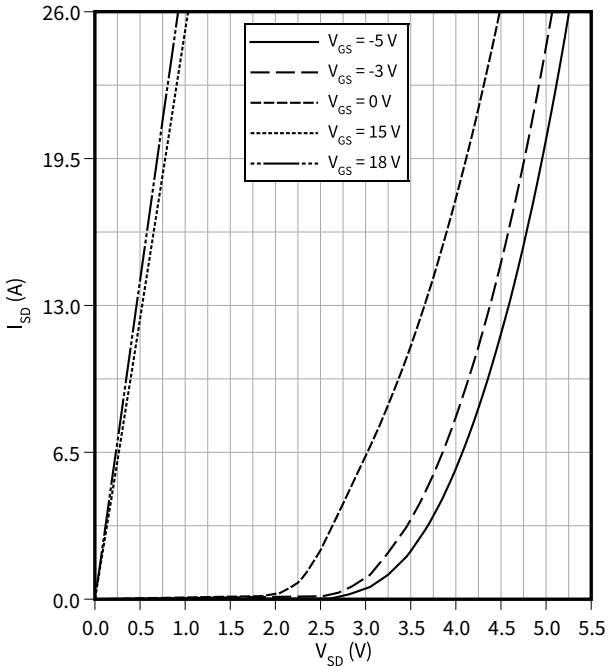
$Z_{th} = f(t)$



Forward characteristic body diode (typical), MOSFET, T5-T8

$I_{SD} = f(V_{SD})$

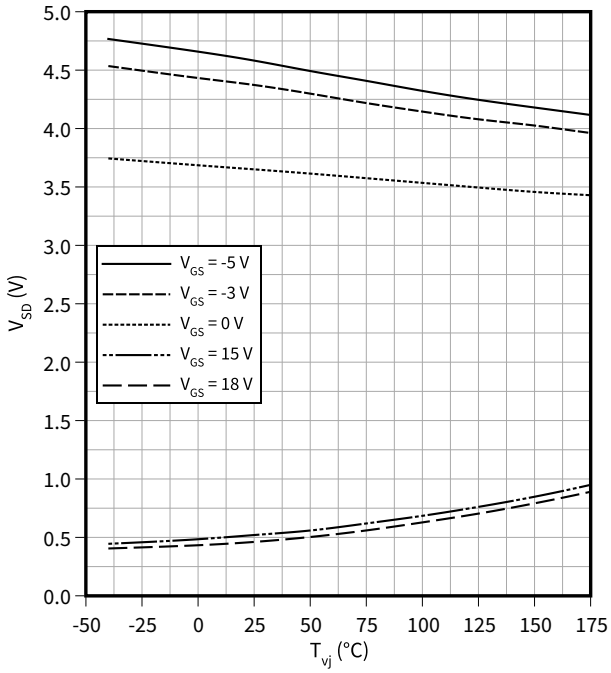
T_{vj} = 25 °C



Forward voltage of body diode (typical), MOSFET, T5-T8

$V_{SD} = f(T_{vj})$

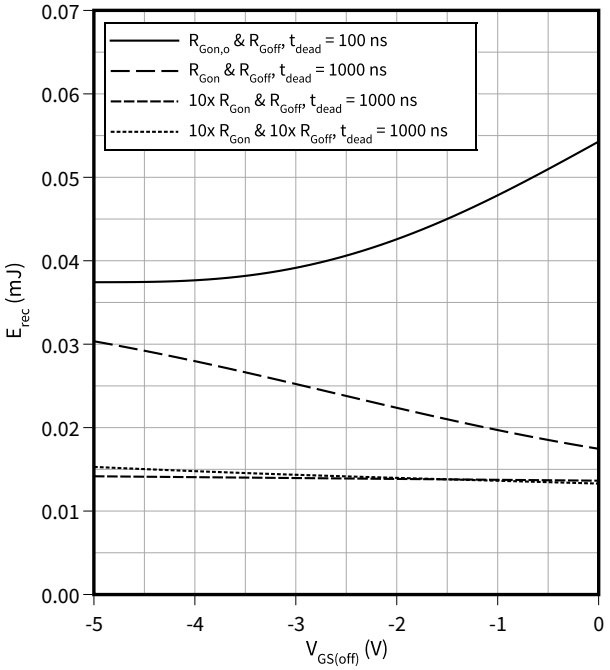
I_{SD} = 13 A



Switching losses body diode (typical), MOSFET, T5-T8

$E_{rec} = f(V_{GS(off)})$

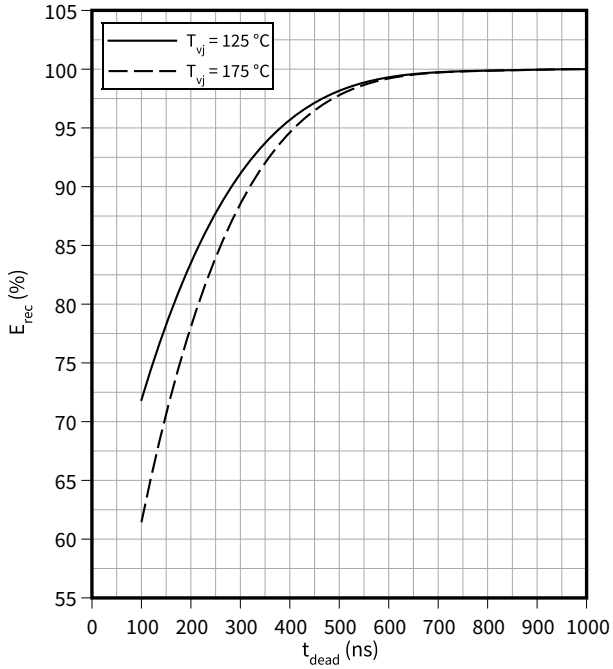
R_{Goff} = 1.6 Ω, R_{Gon} = 13 Ω, $V_{GS(on)}$ = 18 V, I_{SD} = 13 A, $R_{Gon,o}$ = 8.2 Ω, V_{DD} = 400 V, T_{vj} = 175 °C



Switching losses body diode (typical), MOSFET, T5-T8

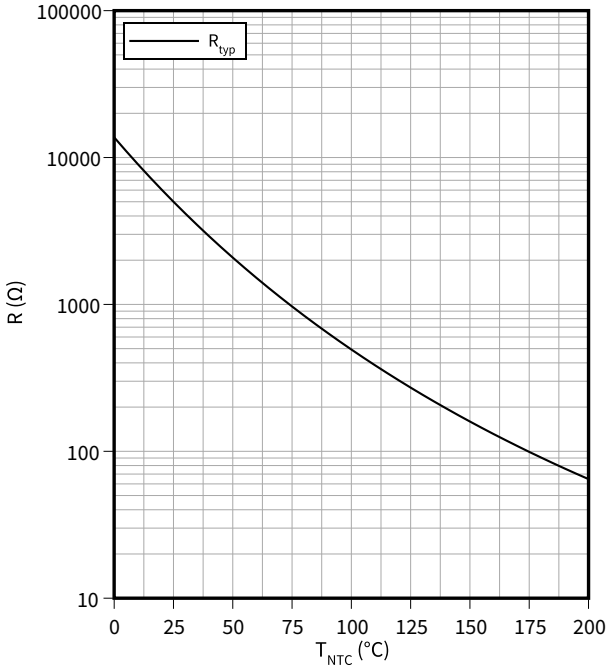
$E_{rec} = f(t_{dead})$

R_{Gon} = 13 Ω, I_D = 13 A, V_{DD} = 400 V, V_{GS} = -3/18 V



Temperature characteristic (typical), NTC-Thermistor

$R = f(T_{NTC})$



8 Circuit diagram

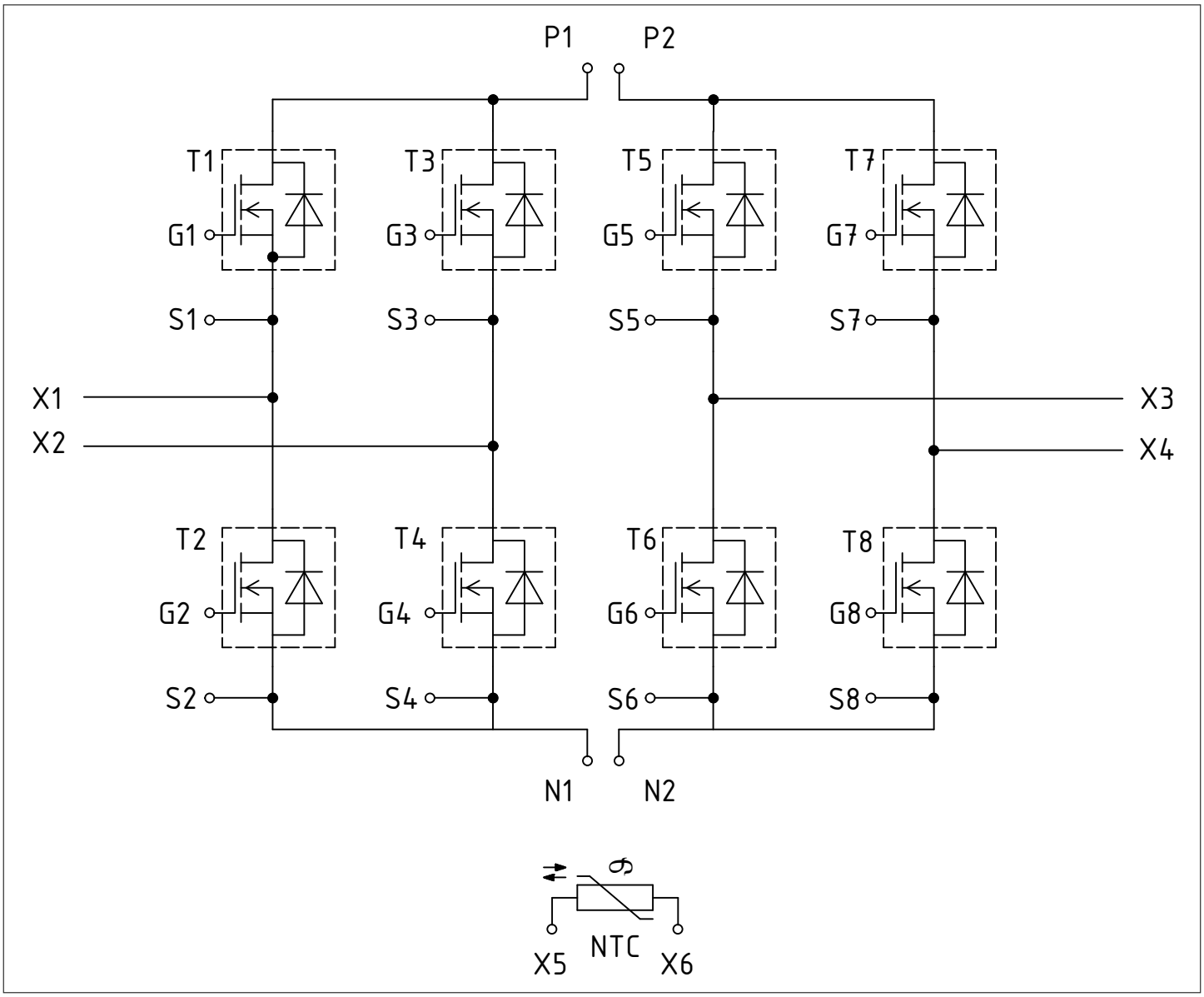


Figure 1

9 Package outlines

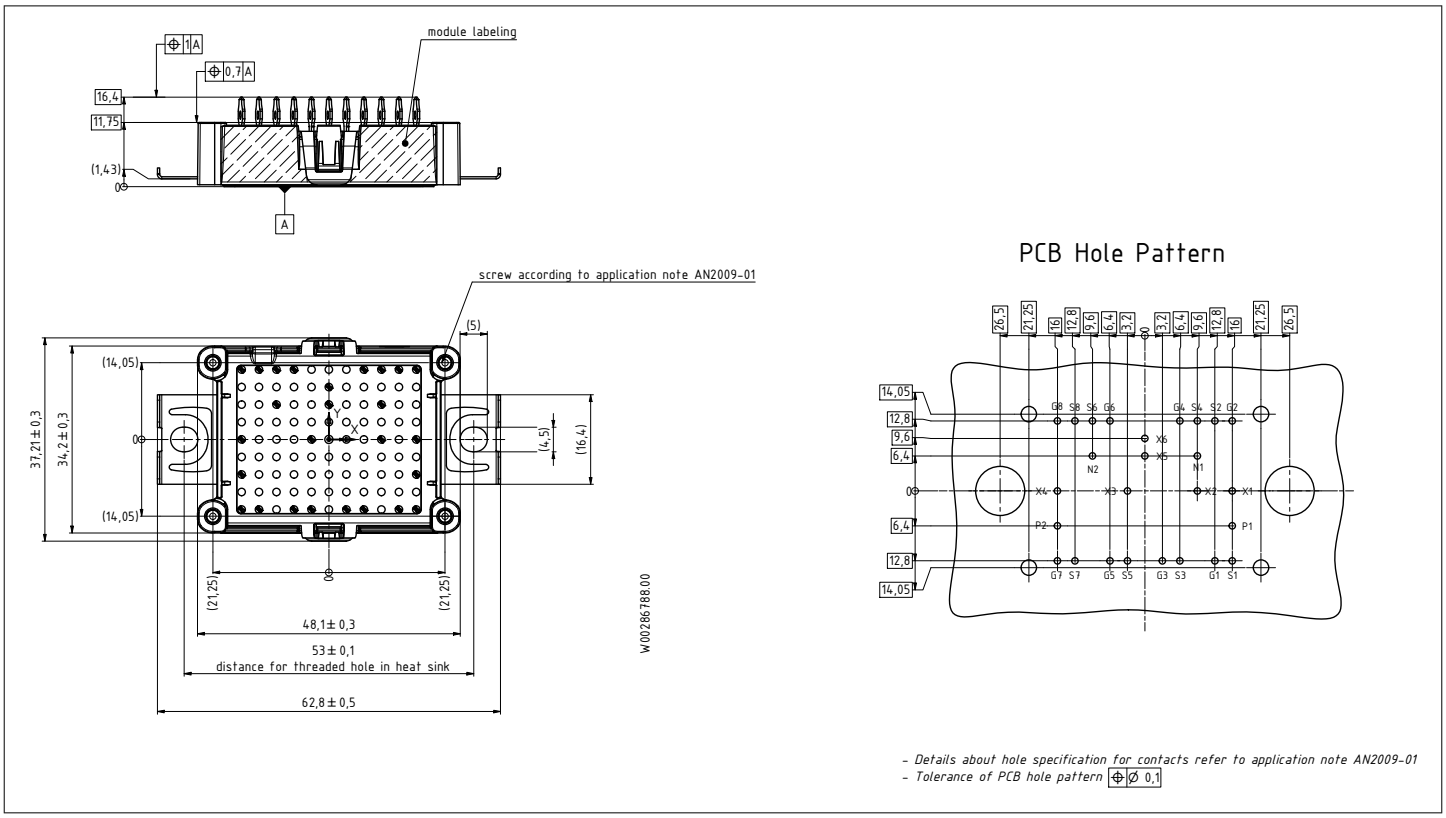


Figure 2

10 Module label code

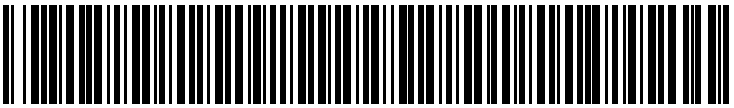
Module label code			
Code format	Data Matrix		Barcode Code128
Encoding	ASCII text		Code Set A
Symbol size	16x16		23 digits
Standard	IEC24720 and IEC16022		IEC8859-1
Code content	*Content* Module serial number Module material number Production order number Date code (production year) Date code (production week)	*Digit* 1 – 5 6 - 11 12 - 19 20 – 21 22 – 23	*Example* 71549 142846 55054991 15 30
Example	 7154914284655054991530	 7154914284655054991530	

Figure 3

Revision history

Document revision	Date of release	Description of changes
0.10	2025-05-27	Target datasheet
0.20	2026-04-30	Preliminary Datasheet
1.00	2026-05-13	Final Datasheet

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